

<b>Notice of References Cited</b>	Application/Control No. 09/634,387	Applicant(s)/Patent Under Reexamination AIHARA ET AL.
	Examiner Gregory B Sefcheck	Art Unit 2662

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,658,013 B1	12-2003	de Boer et al.	370/404
	B	US-6,600,719 B1	07-2003	Chaudhuri, Sid	370/228
	C	US-6,542,461 B1	04-2003	Faye et al.	370/225
	D	US-6,442,131 B1	08-2002	Kondo, Toshiya	370/218
	E	US-6,353,593 B1	03-2002	Chen et al.	370/216
	F	US-6,317,414 B1	11-2001	Naohiro, Shimada	370/222
	G	US-6,049,523 A	04-2000	Anderson et al.	370/217
	H	US-5,805,568 A	09-1998	Shinbashi, Masahiro	370/223
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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